ADC STATUS REPORT, BCM1F

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> DRAFT



Structure

- > Baseline method
- Signal processing and Amplitude spectra
- > Baseline Tool
- > Bunch structure repetition as in TDC
- Intrinsic time distribution
- Radiation Aging
- Lumi problems -> Dead time missing now



Baseline Calculation



Baseline is calculated for each single trigger within abort gap

Baseline stability shown on the histogram with blue

Averaging last 100 baselines for each trigger improves baseline stability – red color





Amplitude Spectrum



- Baseline stability is important for amplitude spectra
- ➢Blue single baseline determination ➢Red – 100 BL averaging

Improves pedestal & saturation peak

Length of signal over threshold as a function of signal amplitude.

Most of long signals are in saturation Low threshold 0.1 ADC counts leads to overlapping of signals and shows double and triple peaks Olga Novgorodova | ADC status report | 02/02/2012 |



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By setting fixed threshold arriving time distribution has a jitter Constant Fraction Discrimination – CFD Time over threshold ~40ns for 50% of amplitude.



Baseline Tool



Full 2011 baseline tool for BCM1F was operated

BL moved down in10ADC counts

Low values are corresponding switched off HV



Bunch structure repetition as in TDC



Finding of ADC signals with fixed threshold



Bunch structure repetition as in TDC



Time Resolution with Test Pulses

Arriving Time Resolution - in

respect to ADC trigger (Test pulses were feed to ADC trigger in and 1ADC channel)

Intrinsic Time Resolution – two

ADC channels in respect to each other (Test pulses were feed to 2ADC channels)

Jitter due to ADC trigger chock – can be up to 16 ns



Intrinsic Time Resolution, CFD FlatTop measurements



Over several Fills at Flat Top stage ADC data was recorded Coincidence of two signals in two ADC channels are taken Time over threshold is calculated as 50% of amplitude with CFD method Difference between cannel ~12 ns ITR = 2.18 ± 0.16 Previous result was 1,8 ns (Ringo Schmidt 2009)



Test Pulses Monitoring



➢Over 2011 test pulses measurements were done regularly to monitor FEelectronics degradation

Dependence of test pulses amplitude in respect to baseline shown as a function of integrated luminosity. -1 point shows values of test pulses amplitudes measured in 2009.



HV scan for BCM1F





Dead Time Correlation with collision rates



Has to be divided by 100.



Conclusions



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